PCN Number:			1 20130509001			PCN Date:	1.05/14/2013			
Title: Qualification SOIC Package			юр	per wire a	as alterna	te bonding mat	erial	for select	ed pr	oducts in
Customer Contact:		PC	N N	lanager_	Phone:	+1(214)480-6	037	Dept:	Qua	lity Services
Proposed 1 st Ship Da		te:		06/14/20	013 Es	stimated Sam	ple <i>A</i>	vailabilit	y:	05/10/2013
Change Type:										
Assembly Site			\boxtimes	Assemi	Assembly Process		Assembly Materials			
Design				Electric	Electrical Specification		Mechanical Specification			
Test Site				Packing	Packing/Shipping/Labeling T		Test Process			
Wafer Bump Site				Wafer I	Wafer Bump Material		Wafer Bump Process			
Wafer Fab Site					Wafer Fab Materials W			Wafer Fab Process		
	PCN Details									

Description of Change:

To qualify Cu wire as alternative bond material for selected products in SOT23 package. All the devices in this notification were included in either Forecast PCN20123101B published on March 20, 2012 or PCN20125303A published on July 31, 2012 which was both issued from the National Semiconductor PCN system.

	From	То
Wire	Au, 0.9mil & 1.0mil	Cu, 0.96 mil or Au, 0.9mil & 1.0mil
Mold Compound	8097131	8097131
Mount Compound	8075531	8075531
Leadframe Finish	Matte Sn or SnPb	Matte Sn or SnPb

Reason for Change:

Continuity of supply.

- 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties
- 2) Maximize flexibility within our Assembly/Test production sites.
- 3) Cu is easier to obtain and stock

Anticinated	impact on Fit	Form, Function,	Quality or I	Reliability	(nositive /	negative).
Allticipateu	illipact on i it,	i oriii, runction,	Ouality of I	venapility i	DOSILIVE /	negative /.

None

Changes to product identification resulting from this PCN:

None

Product Affected:

See page 2

Qualification Data: Approved 04/12/2013

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qualification Device: LM4041AIM3-1.2 (MSL 1-260c)

Package Construction Details

Assembly Site:	TIEM	Mold Compound:	8097131
# Pins-Designator, Family:	3-DBZ, SOT	Mount Compound:	8075531
Leadframe (Finish, Base):	SnPb, Cu	Bond Wire:	0.96 Mil Dia., Cu

Plan **Qualification: ☐** Test Results

Doliability Toot	Conditions	Sample Size / Fail					
Reliability Test	Conditions	Lot 1	Lot 2	Lot 3			
**High Temp. Storage Bake	150C (500, 1000hrs)	80/0					
**Biased HAST	130C/85%RH (96Hrs)	80/0	80/0	80/0			
**T/C -65C/150C	-65C/+150C (500 Cyc)	80/0	80/0	80/0			
**ACLV 121C/100%RH, 2ATM	121C, 2 atm (96 Hrs)	80/0	80/0	80/0			
Bond-pull strength	2 bonds per corner, 1 in middle	pass	pass	pass			
Notes: **Tests received preconditioning sequence: MSL1-260C							

Reference Qualification Data: Approved 12/14/2012

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qualification Device: LP3985IM5X-5.0 (MSL 1-260c)

Package Construction Details

r ackage construction betains							
Assembly Site:	TIEM	Mold Compound:	8097131				
# Pins-Designator, Family:	5-DBV, SOT	Mount Compound:	8075531				
Leadframe (Finish, Base):	SnPb, Cu	Bond Wire:	0.96 Mil Dia., Cu				

Qualification: Plan **Test Results**

Doliobility Toot	Conditions	Sample Size / Fail				
Reliability Test	Conditions	Lot 1	Lot 2	Lot 3		
**Autoclave 121C	121C, 2 ATM (96 hrs)	80/0	79/0	79/0		
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0	78/0	80/0		
Notes: **Tests received preconditioning sequence: MSL2 2600						

Tests received preconditioning sequence: MSL2-2600

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com